

**Search Notes**

Application/Control No.

10/560,976

Examiner

TAN Q. NGUYEN

Applicant(s)/Patent under  
Reexamination

WEIS ET AL.

Art Unit

3661

**SEARCHED**

Class	Subclass	Date	Examiner
701	1,2,200 211,207 117,118	7/23/2008	TN
340	992,905		
	995.13		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
701	1,2,117	8/3/2008	TN
340	992		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR